

HM62W8511H Series

4M High Speed SRAM (512-kword \times 8-bit)

HITACHI

ADE-203-750D (Z)

Rev. 1.0

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Description

The HM62W8511H is a 4-Mbit high speed static RAM organized 512-kword \times 8-bit. It has realized high speed access time by employing CMOS process (4-transistor + 2-poly resistor memory cell) and high speed circuit designing technology. It is most appropriate for the application which requires high speed, high density memory and wide bit width configuration, such as cache and buffer memory in system. The HM62W8511H is packaged in 400-mil 36-pin SOJ for high density surface mounting.

Features

- Single supply : 3.3 V \pm 0.3 V
- Access time 12/15 ns (max)
- Completely static memory
 - No clock or timing strobe required
- Equal access and cycle times
- Directly TTL compatible
 - All inputs and outputs
- Operating current : 150/130 mA (max)
- TTL standby current : 60/50 mA (max)
- CMOS standby current : 5 mA (max)
 - : 1 mA (max) (L-version)
- Data retension current : 0.6 mA (max) (L-version)
- Data retension voltage : 2 V (min) (L-version)
- Center V_{CC} and V_{SS} type pinout

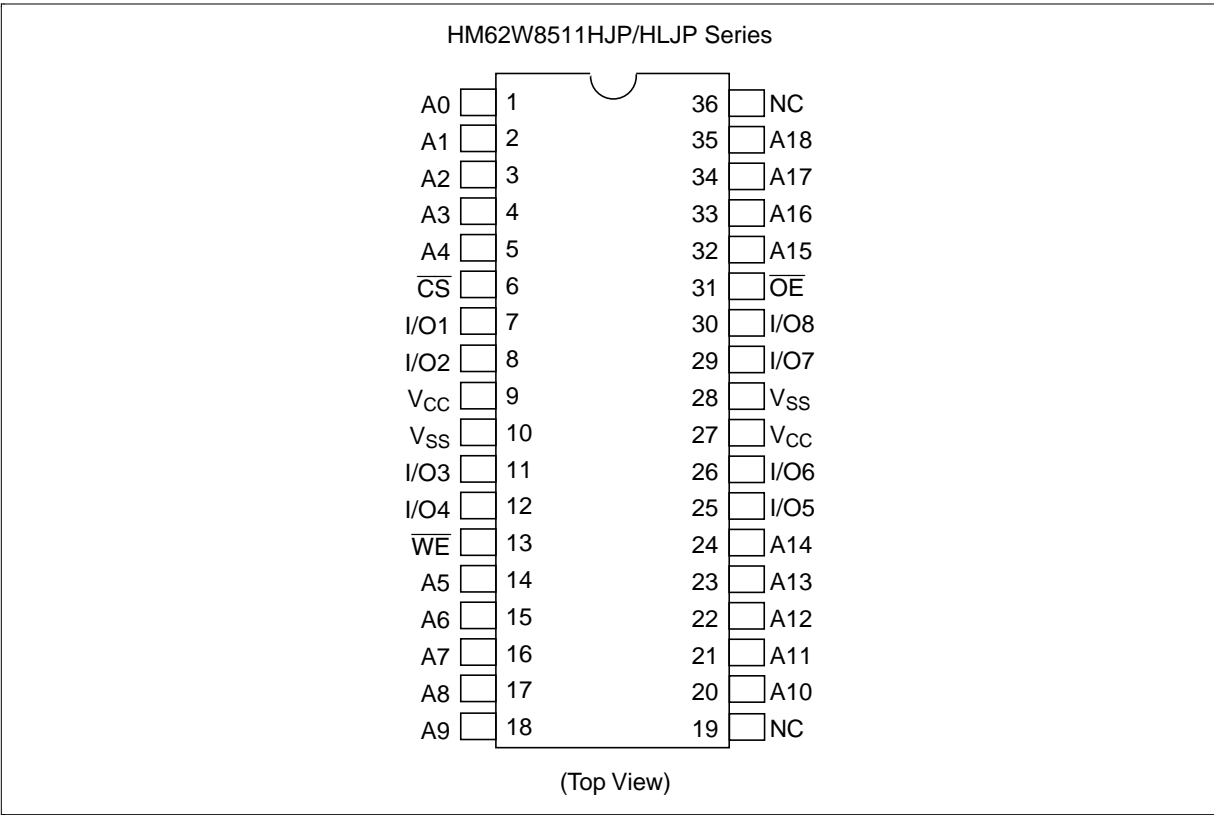


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Ordering Information

Type No.	Access time	Package
HM62W8511HJP-12	12 ns	400-mil 36-pin plastic SOJ (CP-36D)
HM62W8511HJP-15	15 ns	
HM62W8511HLJP-12	12 ns	
HM62W8511HLJP-15	15 ns	

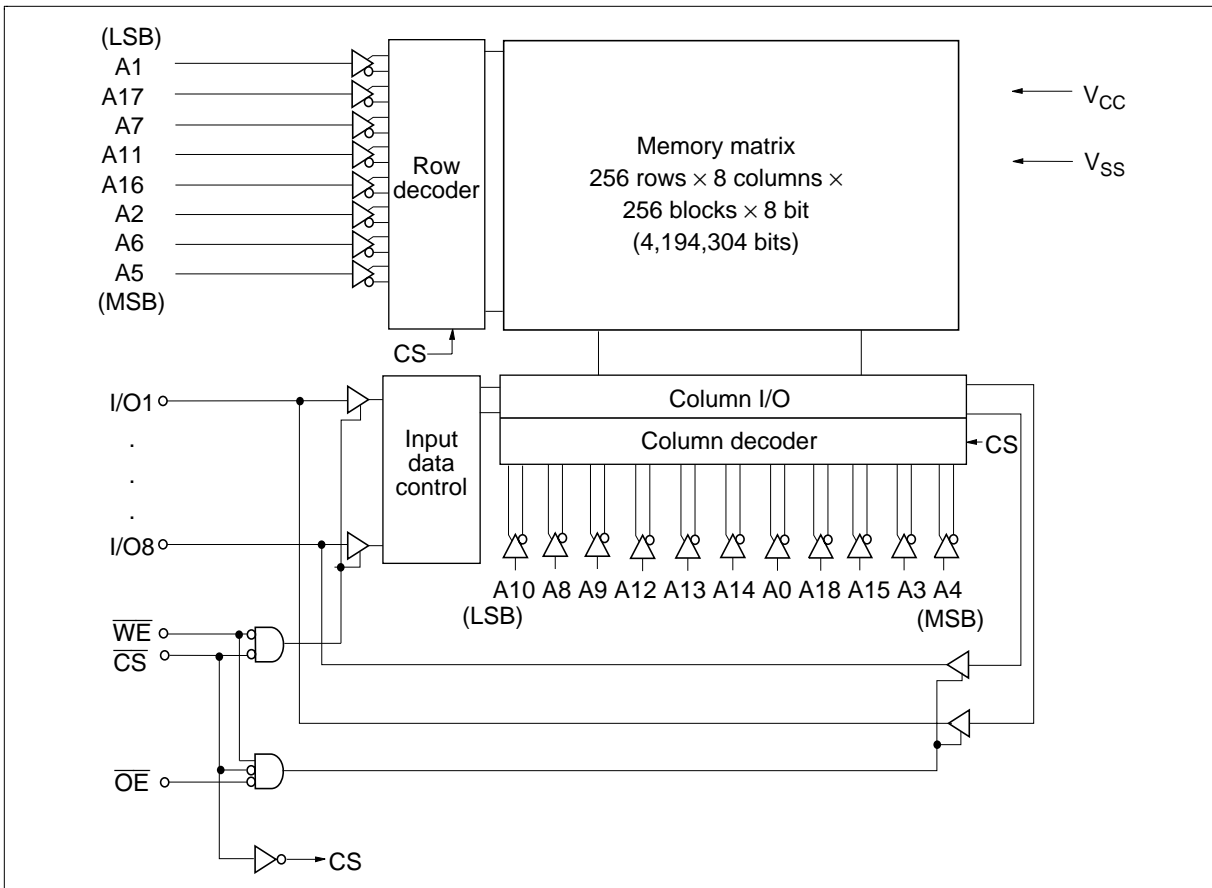
Pin Arrangement



Pin Description

Pin name	Function
A0 to A18	Address input
I/O1 to I/O8	Data input/output
\overline{CS}	Chip select
\overline{OE}	Output enable
\overline{WE}	Write enable
V_{CC}	Power supply
V_{SS}	Ground
NC	No connection

Block Diagram



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Operation Table

$\overline{\text{CS}}$	$\overline{\text{OE}}$	$\overline{\text{WE}}$	Mode	V _{CC} current	I/O	Ref. cycle
H	×	×	Standby	I _{SB} , I _{SB1}	High-Z	—
L	H	H	Output disable	I _{CC}	High-Z	—
L	L	H	Read	I _{CC}	Dout	Read cycle (1) to (3)
L	H	L	Write	I _{CC}	Din	Write cycle (1)
L	L	L	Write	I _{CC}	Din	Write cycle (2)

Note: ×: H or L

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Supply voltage relative to V _{SS}	V _{CC}	−0.5 to +4.6	V
Voltage on any pin relative to V _{SS}	V _T	−0.5* ¹ to V _{CC} +0.5* ²	V
Power dissipation	P _T	1.0	W
Operating temperature	T _{opr}	0 to +70	°C
Storage temperature	T _{stg}	−55 to +125	°C
Storage temperature under bias	T _{bias}	−10 to +85	°C

Notes: 1. V_T (min) = −2.0 V for pulse width (under shoot) ≤ 8 ns
2. V_T (max) = V_{CC}+2.0 V for pulse width (over shoot) ≤ 8 ns

Recommended DC Operating Conditions (T_a = 0 to +70°C)

Parameter	Symbol	Min	Typ	Max	Unit
Supply voltage	V _{CC} * ³	3.0	3.3	3.6	V
	V _{SS} * ⁴	0	0	0	V
Input voltage	V _{IH}	2.2	—	V _{CC} + 0.5* ²	V
	V _{IL}	−0.5* ¹	—	0.8	V

Notes: 1. V_{IL} (min) = −2.0 V for pulse width (under shoot) ≤ 8 ns
2. V_{IH} (max) = V_{CC}+2.0 V for pulse width (over shoot) ≤ 8 ns
3. The supply voltage with all V_{CC} pins must be on the same level.
4. The supply voltage with all V_{SS} pins must be on the same level.

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DC Characteristics (Ta = 0 to +70°C, V_{CC} = 3.3 V ± 0.3 V, V_{SS} = 0V)

Parameter		Symbol	Min	Typ* ¹	Max	Unit	Test conditions
Input leakage current		I _{LI}	—	—	2	μA	V _{in} = V _{SS} to V _{CC}
Output leakage current		I _{LO}	—	—	2	μA	V _{in} = V _{SS} to V _{CC}
Operation power supply current	12 ns cycle	I _{CC}	—	—	150	mA	Min cycle CS̄ = V _{IL} , I _{out} = 0 mA Other inputs = V _{IH} /V _{IL}
	15 ns cycle	I _{CC}	—	—	130		
Standby power supply current	12 ns cycle	I _{SB}	—	—	60	mA	Min cycle CS̄ = V _{IH} , Other inputs = V _{IH} /V _{IL}
	15 ns cycle	I _{SB}	—	—	50		
		I _{SB1}	—	0.05	5	mA	f = 0 MHz V _{CC} ≥ CS̄ ≥ V _{CC} - 0.2 V, (1) 0 V ≤ V _{in} ≤ 0.2 V or (2) V _{CC} ≥ V _{in} ≥ V _{CC} - 0.2 V
			—* ²	0.05* ²	1.0* ²		
Output voltage		V _{OL}	—	—	0.4	V	I _{OL} = 8 mA
		V _{OH}	2.4	—	—	V	I _{OH} = -4 mA

Notes: 1. Typical values are at V_{CC} = 3.3 V, Ta = +25°C and not guaranteed.

2. This characteristics is guaranteed only for L-version.

Capacitance (Ta = +25°C, f = 1.0 MHz)

Parameter		Symbol	Min	Typ	Max	Unit	Test conditions
Input capacitance* ¹		C _{in}	—	—	6	pF	V _{in} = 0 V
Input/output capacitance* ¹		C _{I/O}	—	—	8	pF	V _{I/O} = 0 V

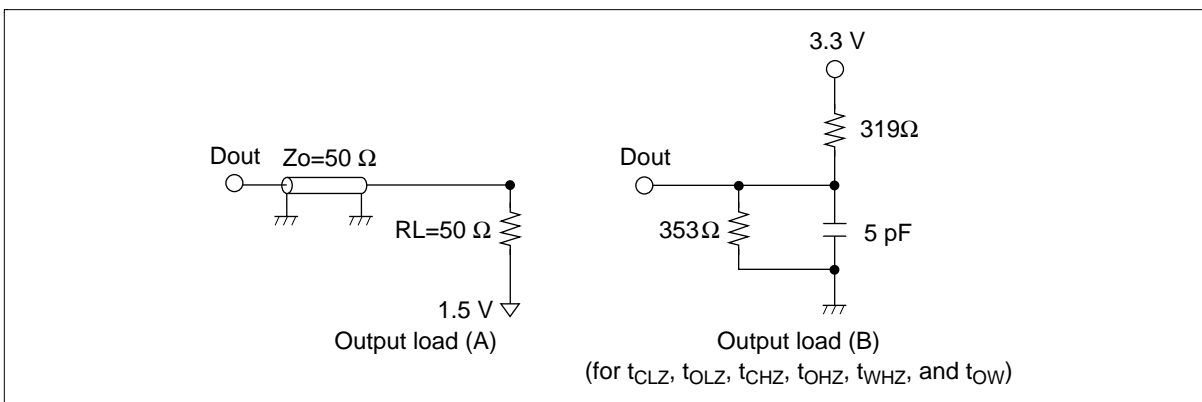
Note: 1. This parameter is sampled and not 100% tested.

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AC Characteristics ($T_a = 0$ to $+70^\circ\text{C}$, $V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$, unless otherwise noted.)

Test Conditions

- Input pulse levels: 3.0 V/0.0 V
- Input rise and fall time: 3 ns
- Input and output timing reference levels: 1.5 V
- Output load: See figures (Including scope and jig)



Read Cycle

		HM62W8511H					
		-12		-15			
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Read cycle time	t _{RC}	12	—	15	—	ns	
Address access time	t _{AA}	—	12	—	15	ns	
Chip select access time	t _{ACS}	—	12	—	15	ns	
Output enable to outpput valid	t _{OE}	—	6	—	7	ns	
Output hold from address change	t _{OH}	3	—	3	—	ns	
Chip select to output in low-Z	t _{CLZ}	3	—	3	—	ns	1
Output enable to output in low-Z	t _{OLZ}	0	—	0	—	ns	1
Chip deselect to output in high-Z	t _{CHZ}	—	6	—	7	ns	1
Output disable to output in high-Z	t _{OHZ}	—	6	—	7	ns	1

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Write Cycle

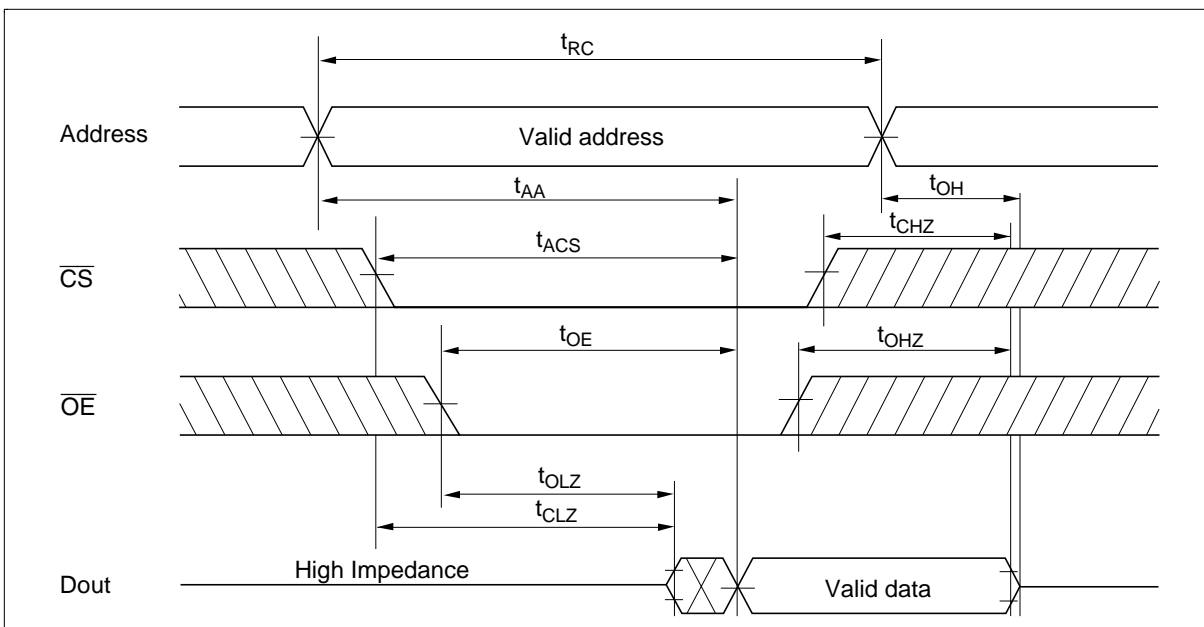
		HM62W8511H					
		-12		-15			
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Write cycle time	t _{WC}	12	—	15	—	ns	
Address valid to end of write	t _{AW}	8	—	10	—	ns	
Chip select to end of write	t _{CW}	8	—	10	—	ns	9
Write pulse width	t _{WP}	8	—	10	—	ns	8
Address setup time	t _{AS}	0	—	0	—	ns	6
Write recovery time	t _{WR}	0	—	0	—	ns	7
Data to write time overlap	t _{DW}	6	—	7	—	ns	
Data hold from write time	t _{DH}	0	—	0	—	ns	
Write disable to output in low-Z	t _{OW}	3	—	3	—	ns	1
Output disable to output in high-Z	t _{OHZ}	—	6	—	7	ns	1
Write enable to output in high-Z	t _{WHZ}	—	6	—	7	ns	1

- Note:
1. Transition is measured ± 200 mV from steady voltage with Load (B). This parameter is sampled and not 100% tested.
 2. Address should be valid prior to or coincident with \overline{CS} transition low.
 3. \overline{WE} and/or \overline{CS} must be high during address transition time.
 4. If \overline{CS} and \overline{OE} are low during this period, I/O pins are in the output state. Then, the data input signals of opposite phase to the outputs must not be applied to them.
 5. If the \overline{CS} low transition occurs simultaneously with the \overline{WE} low transition or after the \overline{WE} transition, output remains a high impedance state.
 6. t_{AS} is measured from the latest address transition to the later of \overline{CS} or \overline{WE} going low.
 7. t_{WR} is measured from the earlier of \overline{CS} or \overline{WE} going high to the first address transition.
 8. A write occurs during the overlap of a low \overline{CS} and a low \overline{WE} . A write begins at the latest transition among \overline{CS} going low and \overline{WE} going low. A write ends at the earliest transition among \overline{CS} going high and \overline{WE} going high. t_{WP} is measured from the beginning of write to the end of write.
 9. t_{CW} is measured from the later of \overline{CS} going low to the the end of write.

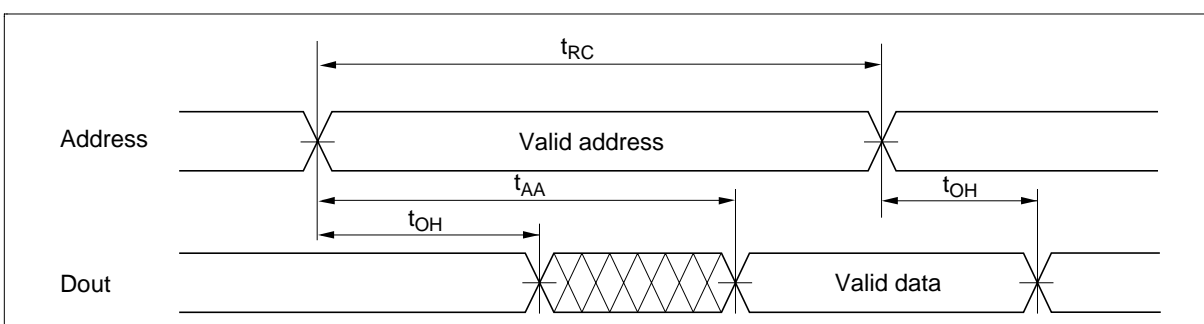
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Timing Waveforms

Read Timing Waveform (1) ($\overline{WE} = V_{IH}$)

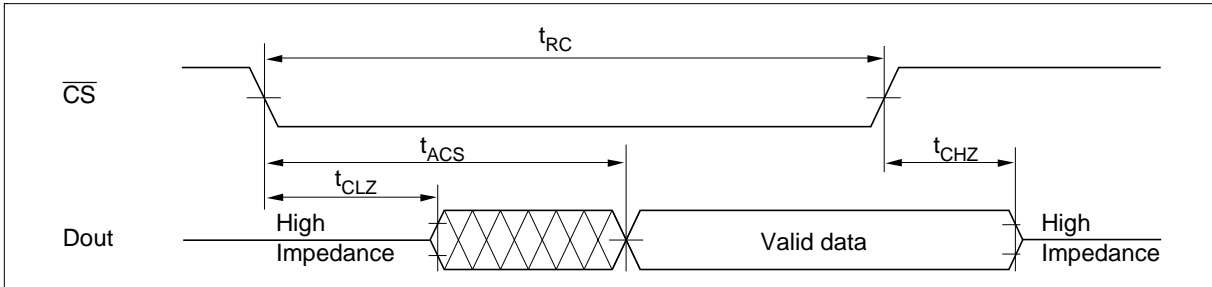


Read Timing Waveform (2) ($\overline{WE} = V_{IH}$, $\overline{CS} = V_{IL}$, $\overline{OE} = V_{IL}$)

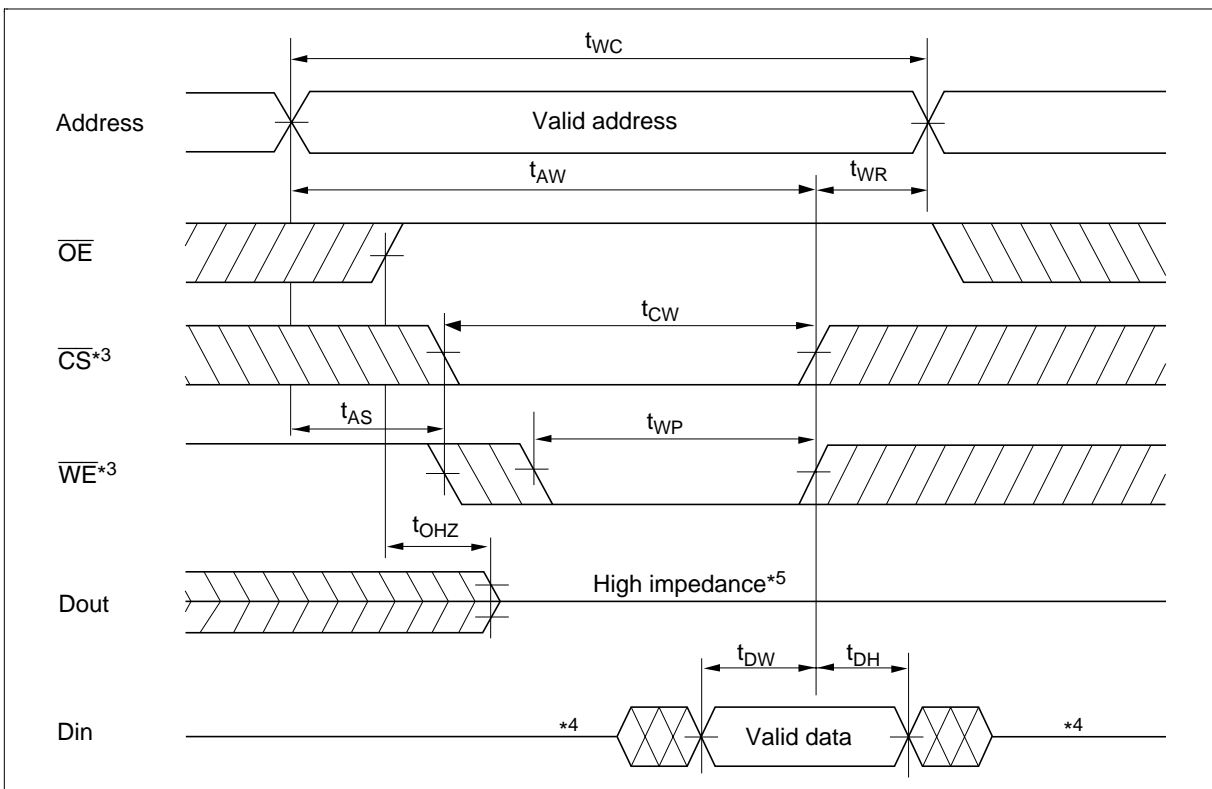


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Read Timing Waveform (3) ($\overline{WE} = V_{IH}$, $\overline{CS} = V_{IL}$, $\overline{OE} = V_{IL}$)*²

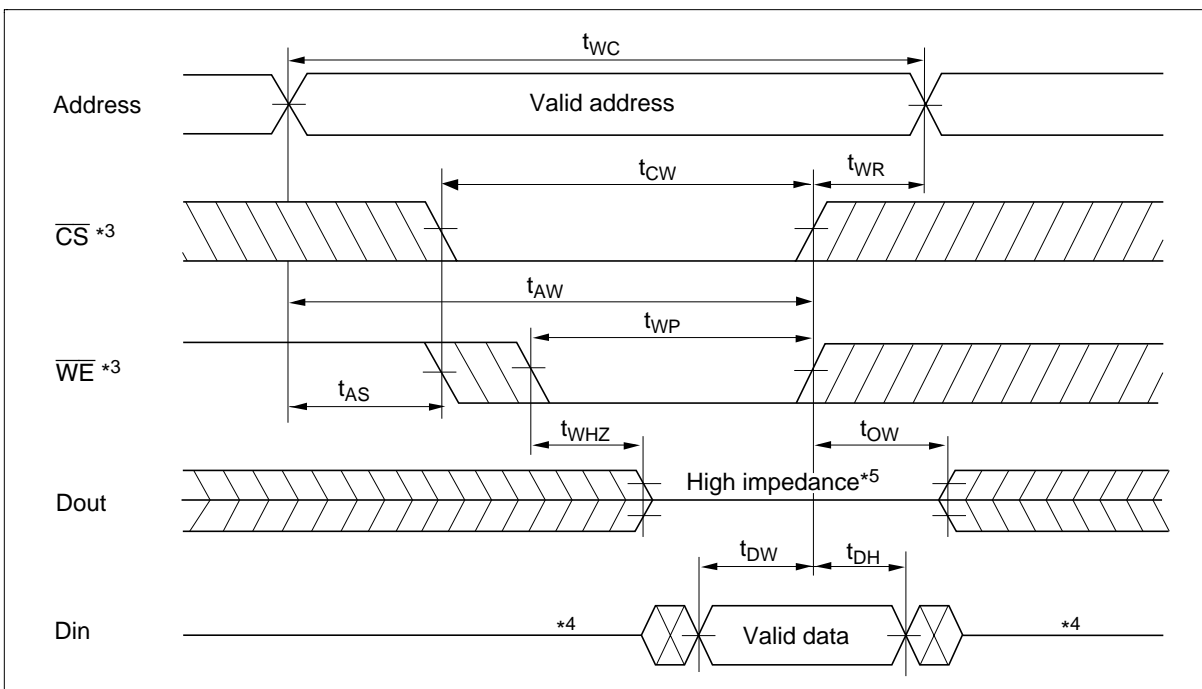


Write Timing Waveform (1) (\overline{WE} Controlled)



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Write Timing Waveform (2) ($\overline{\text{CS}}$ Controlled)



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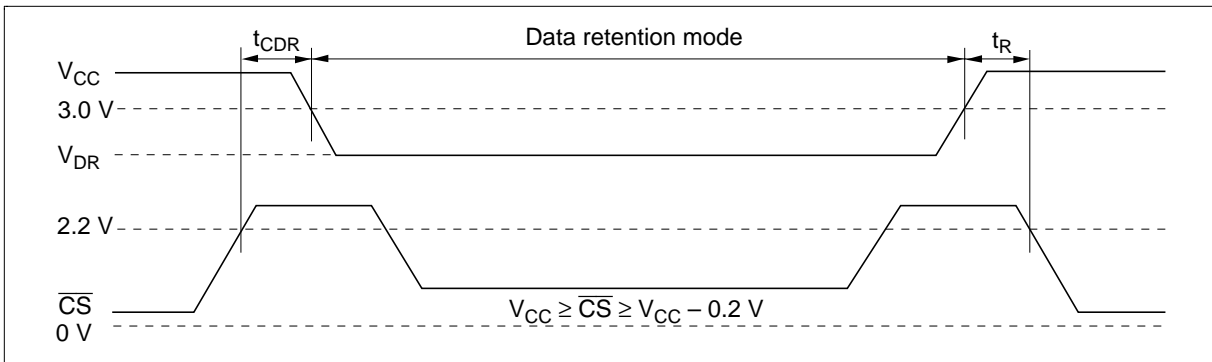
Low V_{CC} Data Retention Characteristics ($T_a = 0$ to $+70^\circ\text{C}$)

This characteristics is guaranteed only for L-version.

Parameter	Symbol	Min	Typ* ¹	Max	Unit	Test conditions
V_{CC} for data retention	V_{DR}	2.0	—	—	V	$V_{CC} \geq \overline{CS} \geq V_{CC} - 0.2 \text{ V}$ (1) $0 \text{ V} \leq V_{in} \leq 0.2 \text{ V}$ or (2) $V_{CC} \geq V_{in} \geq V_{CC} - 0.2 \text{ V}$
Data retention current	I_{CCDR}	—	40	600	μA	$V_{CC} = 3 \text{ V}$, $V_{CC} \geq \overline{CS} \geq V_{CC} - 0.2 \text{ V}$ (1) $0 \text{ V} \leq V_{in} \leq 0.2 \text{ V}$ or (2) $V_{CC} \geq V_{in} \geq V_{CC} - 0.2 \text{ V}$
Chip deselect to data retention time	t_{CDR}	0	—	—	ns	See retention waveform
Operation recovery time	t_R	5	—	—	ms	

Note: 1. Typical values are at $V_{CC} = 3.0 \text{ V}$, $T_a = +25^\circ\text{C}$, and not guaranteed.

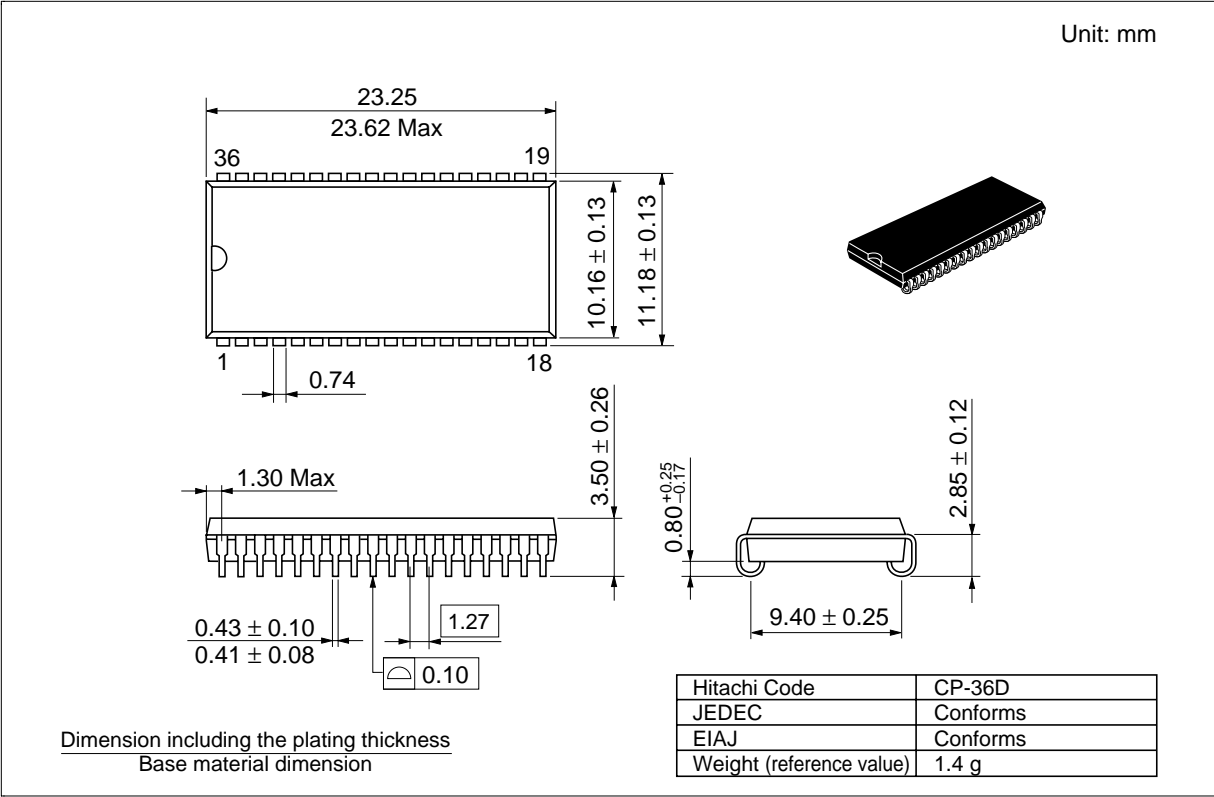
Low V_{CC} Data Retention Timing Waveform



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Package Dimensions

HM62W8511HJP/HLJP Series (CP-36D)



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